


<b>Search Notes</b>  	<b>Application/Control No.</b>  10595157	<b>Applicant(s)/Patent Under Reexamination</b>  TAKENAKA ET AL.
	<b>Examiner</b>  John L Goff	<b>Art Unit</b>  1791

SEARCHED			
Class	Subclass	Date	Examiner
156	307.1,307.7	7/31/08	JLG
Above	UPDATED	1/21/09	JLG
Above	UPDATED	6/1/09	JLG
Above	UPDATED	12/22/09	JLG
Above	UPDATED	1/27/11	JLG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	7/31/08	JLG
Palm Inventor Search	7/31/08	JLG
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	6/1/09	JLG
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	1/27/11	JLG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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